Searcn Notes			

Application/Control No.	Applicant(s)/Patent Reexamination
10/600,711	BAYCHAR,
Examiner	Art Unit

Matthew	D.	Matzek

 Applicant(s)/Pate Reexamination	ent under
BAYCHAR,	
Art Unit	
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	SEARCHED		
Class	Subclass	Date	Examiner
38		1/24/2005	ММ

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

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	DATE	EXMR
EAST	1/24/2005	ММ
PLUS	1/24/2005	ММ
IDS	1/25/2005	ММ
Inventor Search	1/25/2005	мм